



MProbe[®] 20 Thin Film Measurement Systems

It is easy to be an expert with MProbe

Majority of translucent or lightly absorbing films can be measured quickly and reliably: Oxides, Nitrides, Photoresists, Polymers, Semiconductors (Si, aSi, polySi), Compound Semiconductors (AlGaAs, InGaAs, CdTe, CIGS), Hard coatings (SiC, DLC), Polymer films and coatings (Paralene, PMMA, Polyamides), thin metal films and many more.

Thickness Range: 1 nm - 1.8 mm

Wavelength Range: 200nm -1700nm

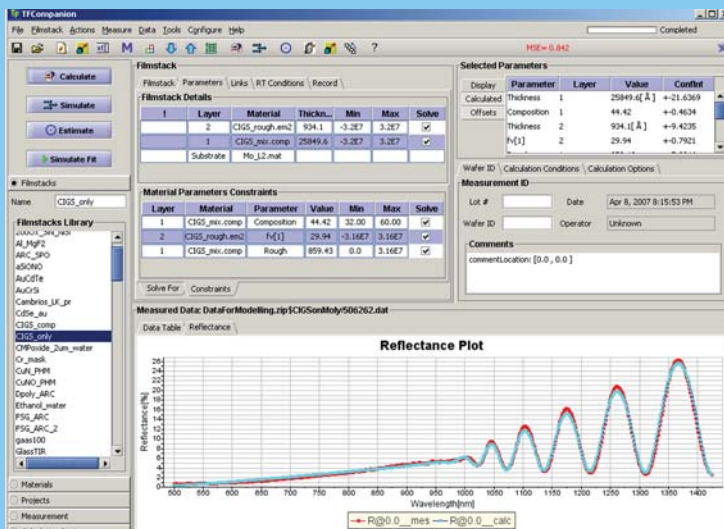
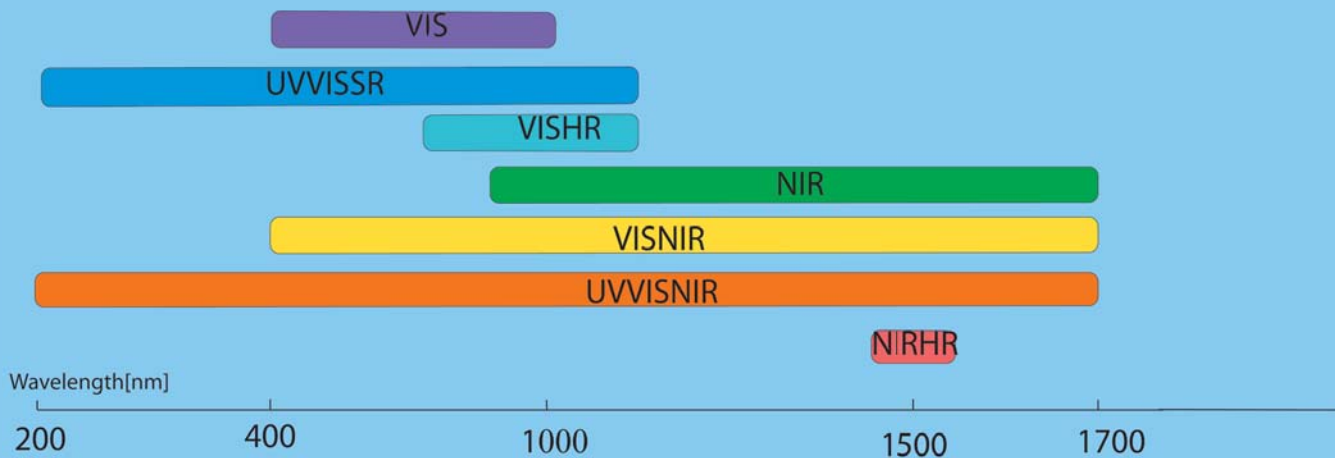
Spot size: 0.5 mm

Thin Solar Cells applications: aSi, TCO, CIGS, CdS, CdTe - full solar stack measurement. LCD, FPD application: ITO, Cell Gaps, Polyamides. Optical Coatings: dielectric filters, hardness coating, anti-reflection coating Semiconductor and dielectrics: Oxides, Nitrides, OLED stack

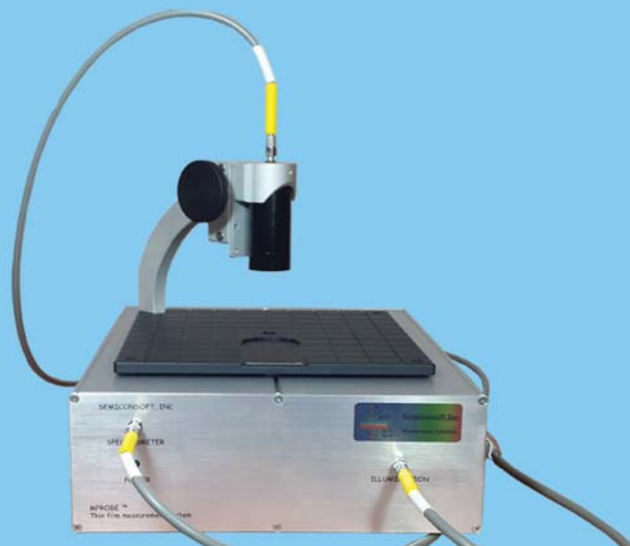
MProbe Advantage:

- Extensive materials library (500+), parametrized materials support
- Real-time, one-click measurement and analysis
- thickness, n&k and roughness measurement
- user friendly desktop software, no expert knowledge required -everybody is an expert
- powerful software tools: simulation, background/ scaling correction, multisample measurement, dynamic measurement
- Measurement history: recall/display measurement results and statistics
- free support and software update for 12 months

Precision	<0.01nm or 0.01%
Accuracy	<0.2% or 1 nm
Stability	<0.02nm or 0.03%
Spot Size	2 mm standard, 0.5 mm with lens
Sample Size	from 5 mm

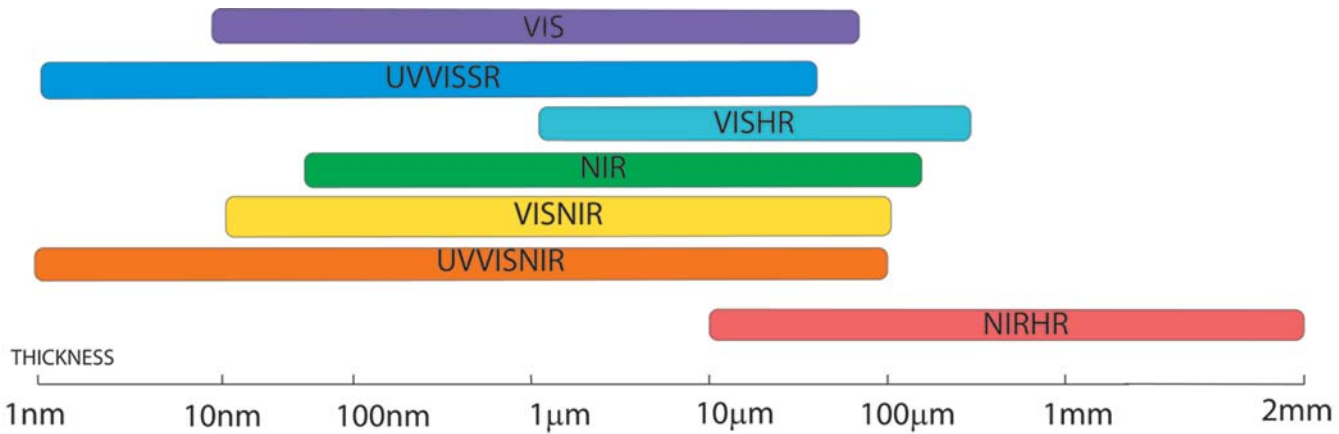


Cds/CIGS stack results
it measured vs. generated data



MProbe system (desktop configuration)

Standard Configurations/Basic Specification



MPROBE 20 line includes different configuration of desktop system. Main standard configurations are described below. See individual system brochure for detailed info

Model	Wavelength range	Spectrometer/Detector/Light source	Thickness range*
VIS	400-1100 nm	Spectrometer F4/Si 3600 pixels/ Tungsten - Halogen light source	10 nm to 75 µm
UVVisSR	200-1000 nm	Spectrometer F4/ Si CCD 2048 pixels/ Deuterium & Tungsten-Halogen light source	1 nm to 75 µm (option: up to 150 µm)
VISHR	700-1100 nm	HR Spectrometer F4/Si 2048 pixels/ Tungsten - Halogen light source	1 µm to 400 µm
NIR	900-1700nm	NIR F4/512 InGaAs PDA/Tungsten-Halogen light source	50 nm-100 µm
VISNIR	400-1700 nm	Spectrometer F4 Si CCD 3600 pixels(Vis channel);NIR F4/512 InGaAs PDA(NIR channel) Tungsten-Halogen light source	10 nm to 100 µm
UVVIS-NIR	200 -1700 nm	Spectrometer F4 Si CCD 2048 pixels(UVVis channel);NIR F4/512 In-GaAs PDA(NIR channel) Deuterium & Tungsten-Halogen light source	1 nm -100 µm
VisLX	400-1100 nm	F4/Si 2048 pixels, Tungsten Halogen light source. High frequency measurement version of MProbe Vis system (LAN interface, 10µs integration time)	10 nm- 70 µm
NIRHR	1500-1550 nm	NIR F4/512 InGaAs PDA/Tungsten-Halogen light source or SLD (super-luminescent diode)	10 µm-1800 µm(quartz) 4 µm -500 µm(Si)

* T, n & k measurement in 25nm - 20µm thickness range.

Maximum thickness limits are listed for R.I.= 1.5

Other configuration are available. OEM inquiries and custom development projects are welcome

One year limited warranty on labor and materials for all system

上海昊量光电设备有限公司

中国区代理

官网: www.auniontech.com 电话: 021-34241961

邮箱: info@auniontech.com

地址: 上海市徐汇区漕宝路 86 号光大会展中心 F 座 3 楼